

July 1987

**GENERAL DESCRIPTION**

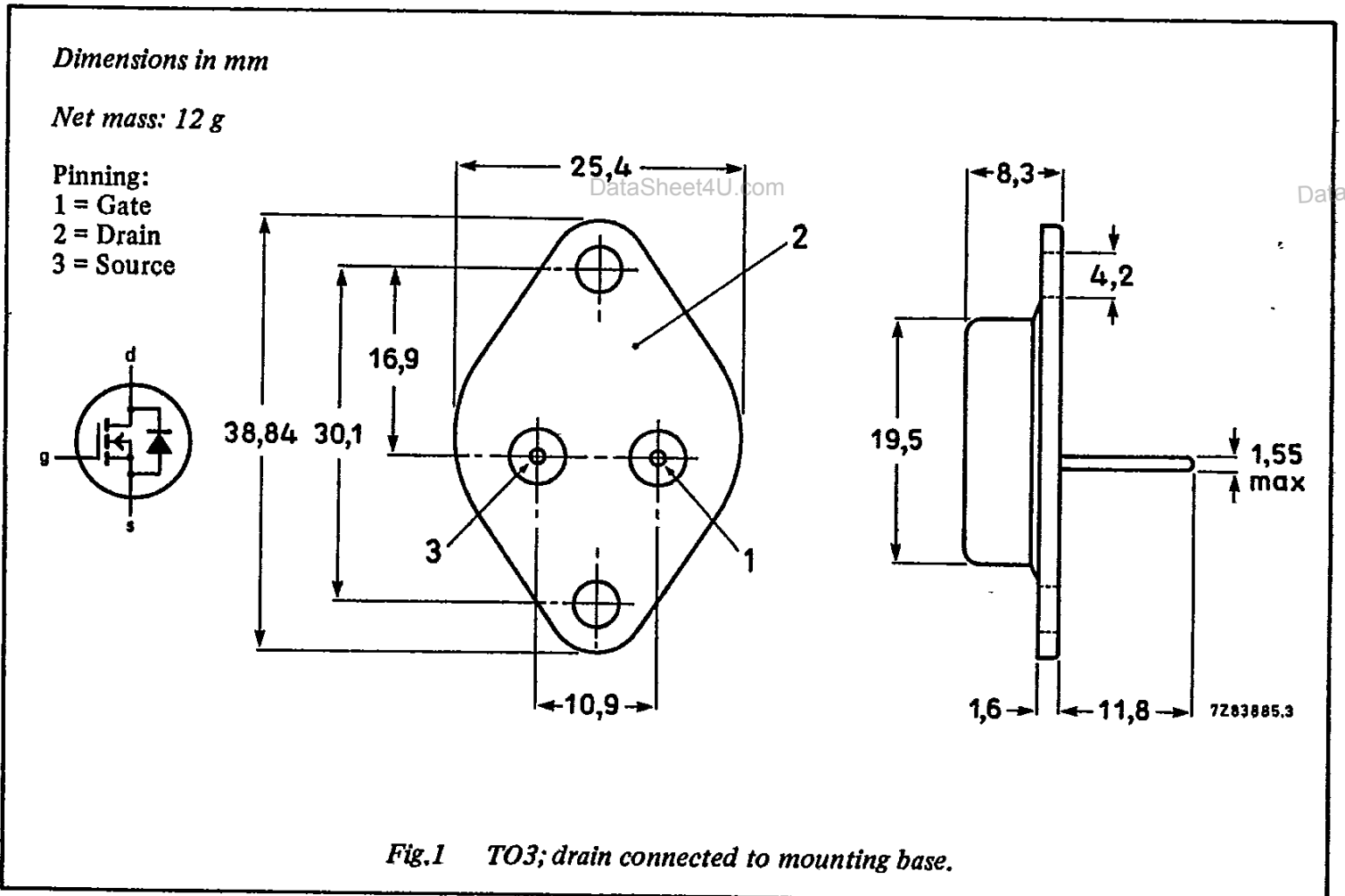
N-channel enhancement mode field-effect power transistor in a metal envelope.

This device is intended for use in Switched Mode Power Supplies (SMPS), motor control, welding, DC/DC and DC/AC converters, and in general purpose switching applications.

**QUICK REFERENCE DATA**

SYMBOL	PARAMETER	MAX.	UNIT
V <sub>DS</sub>	Drain-source voltage	50	V
I <sub>D</sub>	Drain current (d.c.)	45	A
P <sub>tot</sub>	Total power dissipation	125	W
R <sub>DS(ON)</sub>	Drain-source on-state resistance	0,03	Ω

**MECHANICAL DATA**



**Notes**

1. Observe the general handling precautions for electrostatic-discharge sensitive devices (ESDs) to prevent damage to MOS gate oxide.
2. Accessories supplied on request: refer to Mounting instructions for TO3 envelopes.

## Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>DS</sub>	Drain-source voltage	—	—	50	V
V <sub>DGR</sub>	Drain-gate voltage	R <sub>GS</sub> = 20 kΩ	—	50	V
±V <sub>GS</sub>	Gate-source voltage	—	—	20	V
I <sub>D</sub>	Drain current (d.c.)	T <sub>mb</sub> = 25 °C	—	45	A
I <sub>D</sub>	Drain current (d.c.)	T <sub>mb</sub> = 100 °C	—	28,5	A
I <sub>DM</sub>	Drain current (pulse peak value)	T <sub>mb</sub> = 25 °C	—	180	A
P <sub>tot</sub>	Total power dissipation	T <sub>mb</sub> = 25 °C	—	125	W
T <sub>stg</sub>	Storage temperature	—	-55	150	°C
T <sub>j</sub>	Junction temperature	—	—	150	°C

## THERMAL RESISTANCES

From junction to mounting base	R <sub>thj-mb</sub> = 1,0 K/W
From junction to ambient	R <sub>thj-a</sub> = 35 K/W

## STATIC CHARACTERISTICS

T<sub>mb</sub> = 25 °C unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V(BR)DSS	Drain-source breakdown voltage	V <sub>GS</sub> = 0 V; I <sub>D</sub> = 0,25 mA	50	65	—	V
V <sub>GS(TO)</sub>	Gate threshold voltage	V <sub>DS</sub> = V <sub>GS</sub> ; I <sub>D</sub> = 1 mA	2,1	3,0	4,0	V
I <sub>DSS</sub>	Zero gate voltage drain current	V <sub>DS</sub> = 50 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C	—	20	250	μA
I <sub>DSS</sub>	Zero gate voltage drain current	V <sub>DS</sub> = 50 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 125 °C	—	0,1	1,0	mA
I <sub>GSS</sub>	Gate source leakage current	V <sub>GS</sub> = ±20 V; V <sub>DS</sub> = 0 V	—	10	100	nA
R <sub>DS(ON)</sub>	Drain-source on-state resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 22 A	—	0,025	0,03	Ω

## DYNAMIC CHARACTERISTICS

T<sub>mb</sub> = 25 °C unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
g <sub>fs</sub>	Forward transconductance	V <sub>DS</sub> = 25 V; I <sub>D</sub> = 22 A	7,0	18	—	S
C <sub>iss</sub>	Input capacitance	V <sub>GS</sub> = 0 V; V <sub>DS</sub> = 25 V; f = 1 MHz	—	1600	2100	pF
C <sub>oss</sub>	Output capacitance		—	1300	2000	pF
C <sub>rss</sub>	Feedback capacitance		—	500	800	pF
t <sub>d on</sub>	Turn-on delay time	V <sub>DD</sub> = 30 V; I <sub>D</sub> = 3 A;	—	30	45	ns
t <sub>r</sub>	Turn-on rise time	V <sub>GS</sub> = 10 V; R <sub>GS</sub> = 50 Ω;	—	110	170	ns
t <sub>d off</sub>	Turn-off delay time	R <sub>gen</sub> = 50 Ω	—	330	430	ns
t <sub>f</sub>	Turn-off fall time		—	250	330	ns
L <sub>d</sub>	Internal drain inductance	Measured from contact screw on header closer to source pin and centre of die	—	5,0	—	nH
L <sub>s</sub>	Internal source inductance	Measured from source lead 6 mm from package to source bond pad	—	12,5	—	nH

**REVERSE DIODE RATINGS AND CHARACTERISTICS** $T_{mb} = 25\text{ }^{\circ}\text{C}$  unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$I_{DR}$	Continuous reverse drain current	$T_{mb} = 25\text{ }^{\circ}\text{C}$	—	—	45	A
$I_{DRM}$	Pulsed reverse drain current	$T_{mb} = 25\text{ }^{\circ}\text{C}$	—	—	180	A
VSD	Diode forward on-voltage	$I_F = 90\text{ A}; V_{GS} = 0\text{ V}$ $T_j = 25\text{ }^{\circ}\text{C}$	—	1,6	2,4	V
$t_{rr}$	Reverse recovery time	$I_F = 45\text{ A}; T_j = 25\text{ }^{\circ}\text{C}$ $-dI_F/dt = 100\text{ A}/\mu\text{s};$ $T_j = 25\text{ }^{\circ}\text{C}; V_{GS} = 0\text{ V};$	—	150	—	ns
$-Q_{rr}$	Reverse recovery charge	$V_R = 30\text{ V}$	—	1,0	—	$\mu\text{C}$

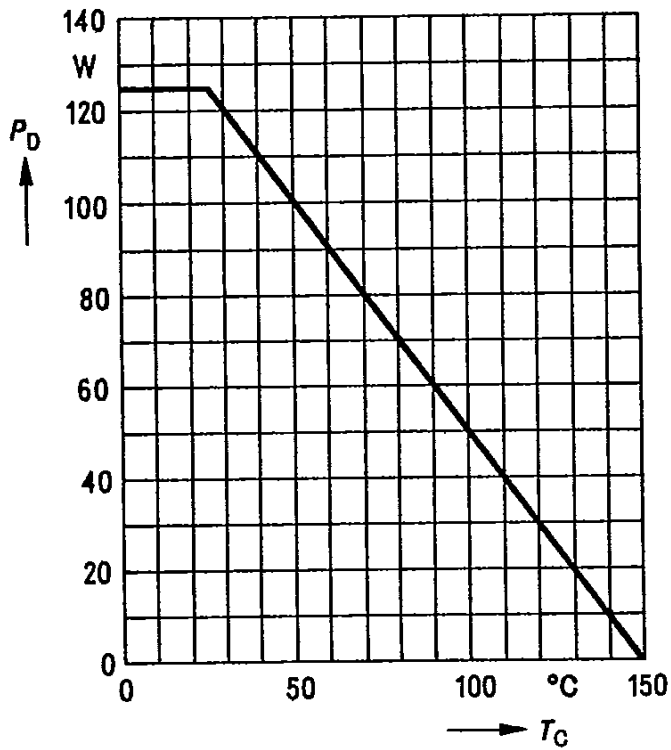


Fig.2 Power dissipation  $P_D = f(T_{mb})$ .

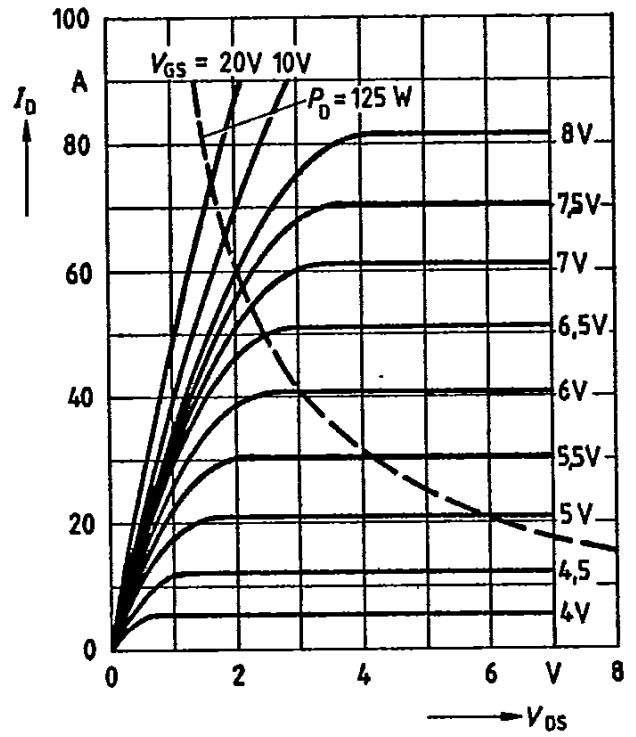


Fig.3 Typical output characteristics  $I_D = f(V_{DS})$   
Parameter:  $V_{GS}$ ; 80  $\mu s$  pulse test;  
 $T_{mb} = 25^\circ C$ .

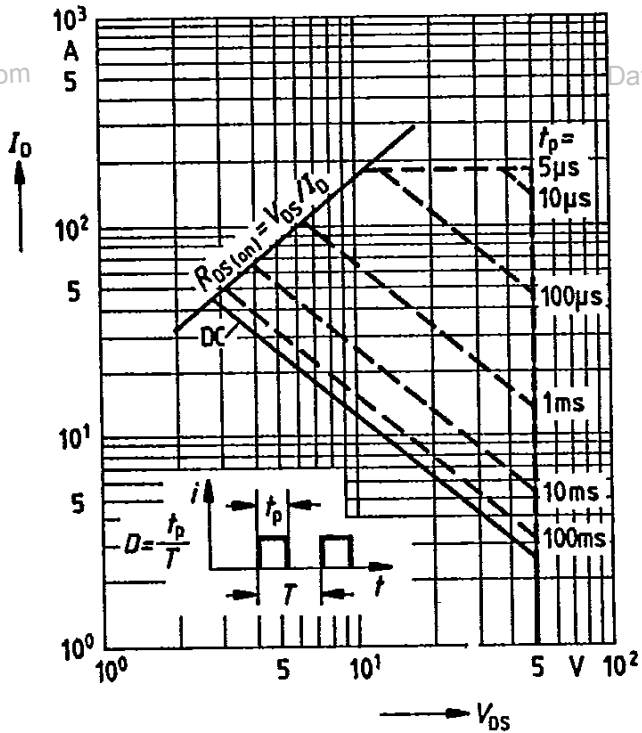


Fig.4 Safe operating area  $I_D(DC)$  and  $I_{DM} = f(V_{DS})$   
Parameter:  $t_p$ ;  $D = 0,01$ ;  $T_{mb} = 25^\circ C$ .

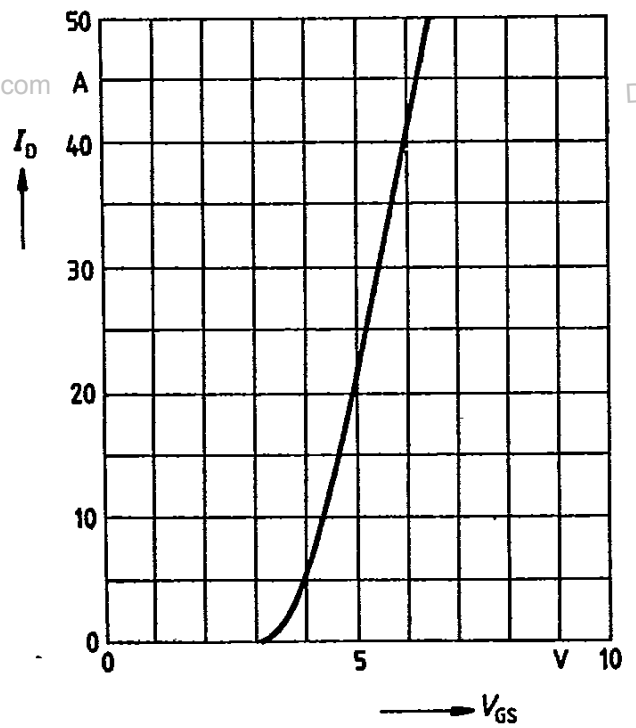


Fig.5 Typical transfer characteristic  $I_D = f(V_{GS})$   
Conditions: 80  $\mu s$  pulse test;  $V_{DS} = 25 V$ ,  
 $T_{mb} = 25^\circ C$ .

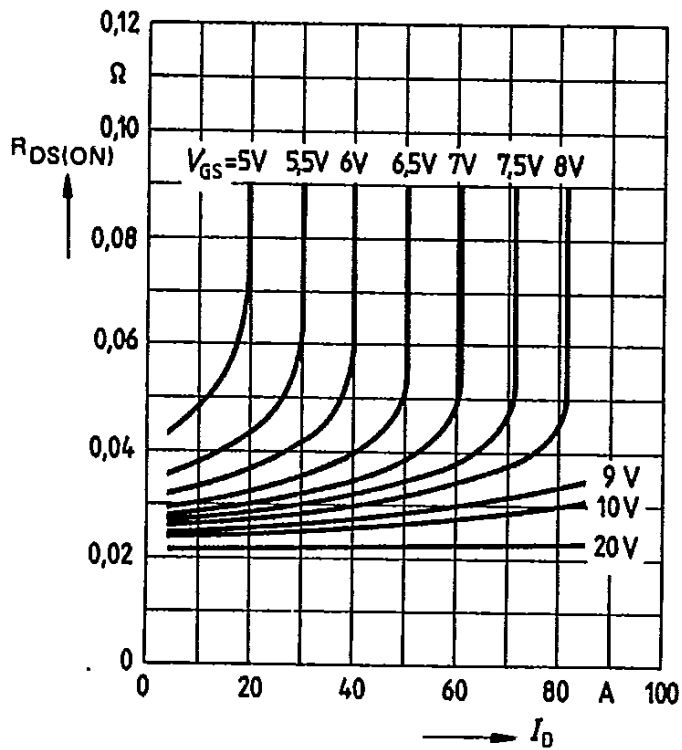


Fig.6 Typical drain-source on-state resistance  
 $R_{DS(ON)} = f(I_D)$   
 Parameter:  $V_{GS}; T_j = 25^\circ C$ .

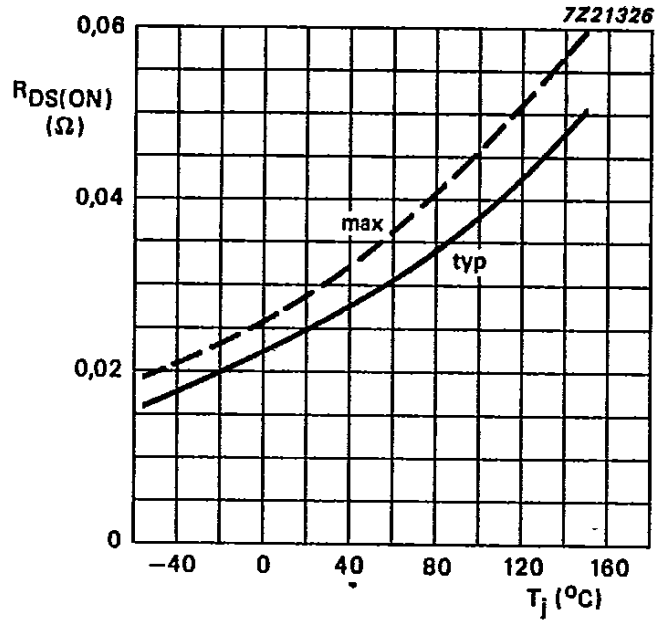


Fig.7 Drain-source on-state resistance  
 $R_{DS(ON)} = f(T_j)$   
 Conditions:  $I_D = 22 A; V_{GS} = 10 V$ .

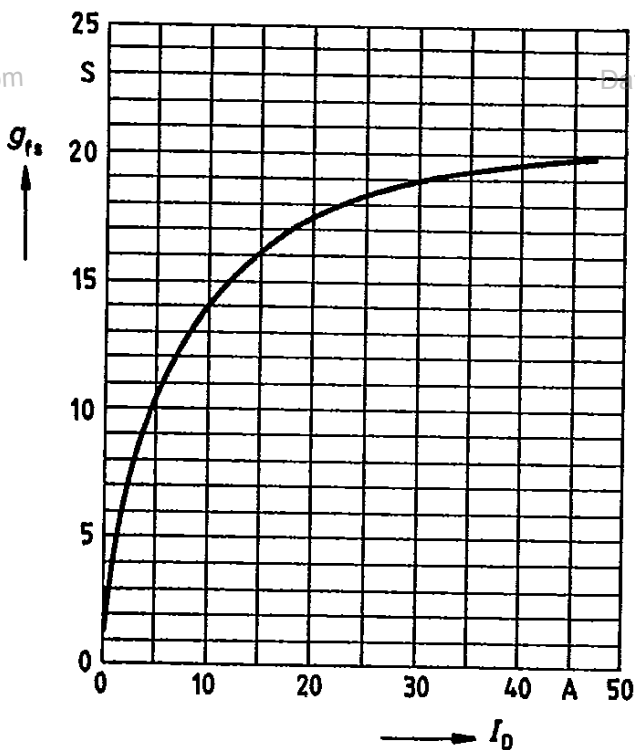


Fig.8 Typical transconductance  $g_{fs} = f(I_D)$   
 Conditions:  $80 \mu s$  pulse test;  
 $V_{DS} = 25 V; T_j = 25^\circ C$ .

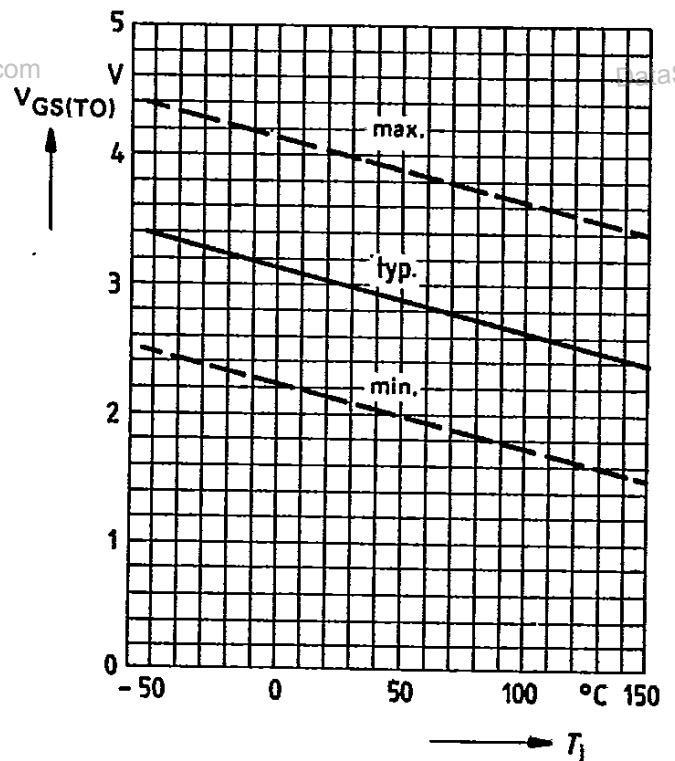


Fig.9 Gate threshold voltage  $V_{GS(TO)} = f(T_j)$   
 Conditions:  $V_{DS} = V_{GS}; I_D = 1 mA$ .

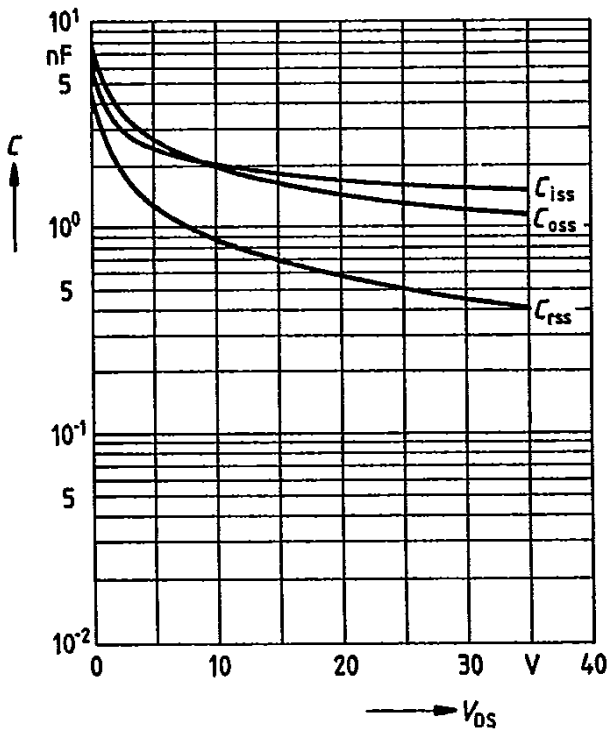


Fig.10 Typical capacitances  $C = f(V_{DS})$   
 Conditions:  $V_{GS} = 0$ ;  $f = 1 \text{ MHz}$ .

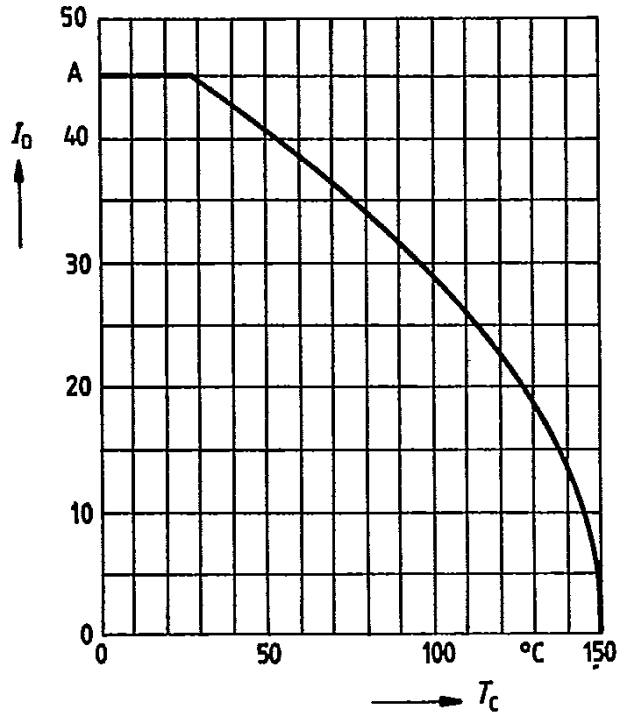


Fig.11 Continuous drain current  $I_D = f(T_{mb})$   
 Conditions:  $V_{GS} \geq 10 \text{ V}$ .

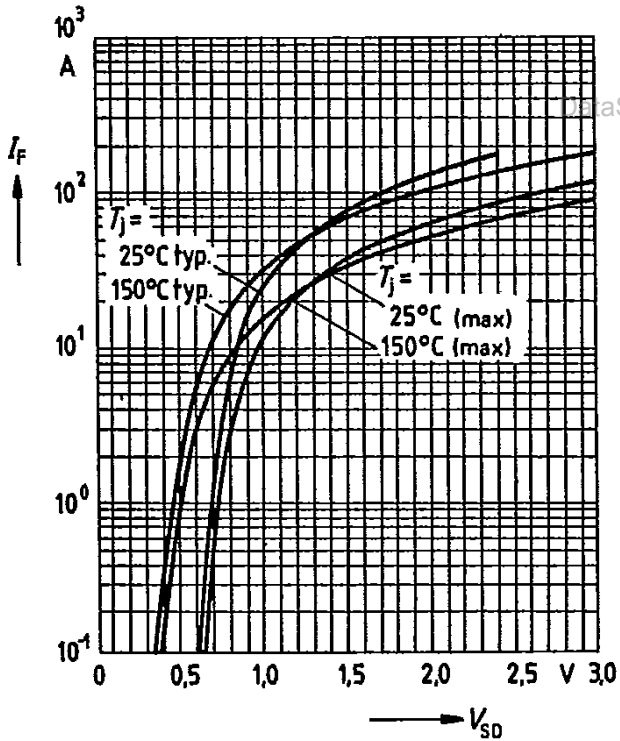


Fig.12 Forward characteristics of reverse diode  
 $I_F = f(V_{SD})$   
 Parameter:  $T_j$ ;  $t_p = 80 \mu\text{s}$ .

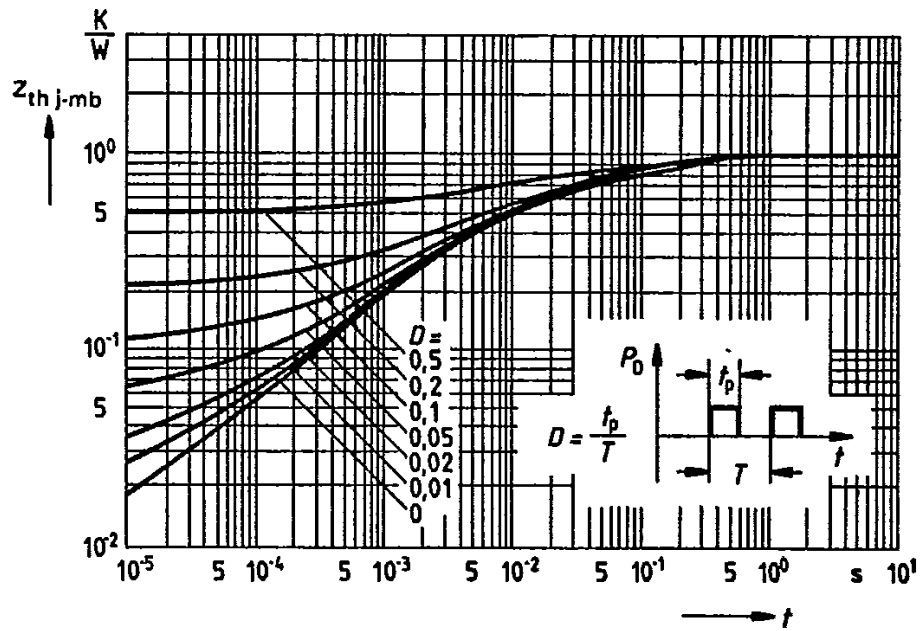


Fig.13 Transient thermal impedance  $Z_{thj-mb} = f(t)$   
Parameter:  $D = t_p/T$ .

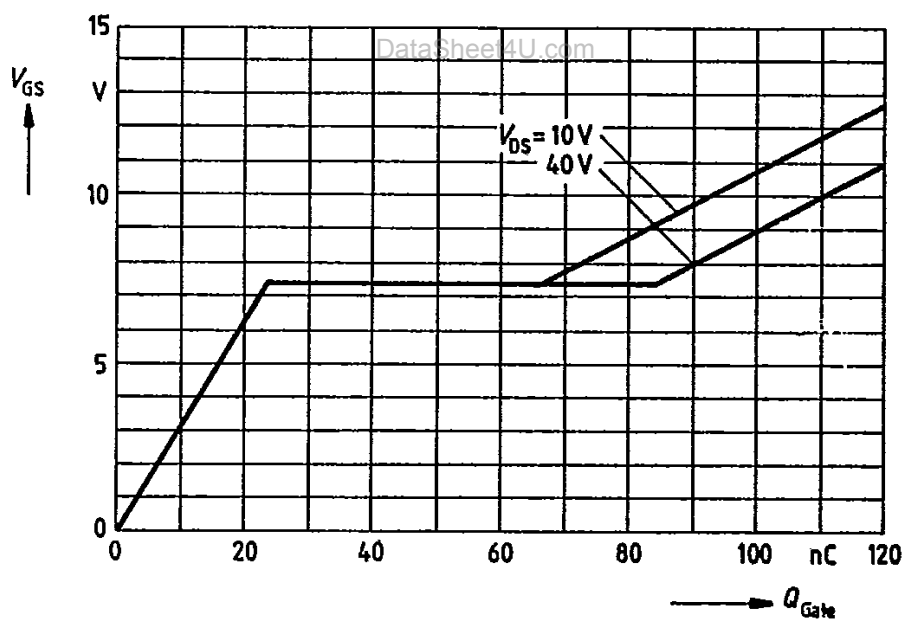


Fig.14 Typical gate-charge  $V_{GS} = f(Q_{Gate})$   
Parameter:  $V_{DS}; I_{DM} = 67,5$  A.